

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/566,705	ICHIKAWA ET AL.	
Examiner	Art Unit	_
Eun H. Chung	2123	

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Class	Subclass	Date	Examiner
703	22	12/29/2006	EHC
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INT	ERFERENC	E SEARCH	ED
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Conducted inventors search	12/29/2006	EHC	
East text search See attached	12/29/2006	EHC	
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